

- **Release of the MP500 PT1NFC to facilitate manufacturing testing of NFC devices**

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Micropross announced today the release of the **MP500 PT1NFC**, a standalone tester aimed at ensuring **highly qualitative test** of the **NFC interface of devices** such as mobile phones, smart watches and even contactless payment terminals, in a **manufacturing context**.

Able to handle the most relevant protocols on the market (ISO 14443 A/B, ISO 15693, Mifare, FeliCa), the **MP500 PT1NFC tests NFC devices operating in the reader/writer mode, as well as in the card mode**. It **performs communication, but also several types of analog measurement**, in just a few seconds.

Philippe Bacle, Micropross' General Manager commented : "With more than 15 years of experience in the test of contactless smart object, we are very happy and proud at Micropross to release the MP500 PT1NFC. Naturally, Micropross has capitalized on the years of experience gathered in the supply of NFC Forum and EMVCo certified conformance test benches to make sure of the reliability of the measurement generated by the MP500 PT1NFC."

It is possible to directly connect to the **MP500 PT1NFC the normative EMVCo and NFC Forum antennas** (poller and listeners can be connected at the same time on the tester's front panel, and the users can correlate the MP500 PT1NFC measurement with the EMVCo and NFC Forum normative test benches) **or one of Micropross' innovative triple antenna**, combining in one single PCB the support of all communication modes.

Users of the MP500 PT1NFC can now **benefit from the support and the experience of their local National Instruments contact persons**, in addition to their traditional Micropross direct and indirect representatives.

Projects such as Apple Pay , Android Pay, or the innovative use cases defined by the NFC Forum will drive the consumer desire for NFC enabled devices. The MP500 PT1NFC will contribute to the success of the mass deployment of the NFC technology by **allowing the industrials to make no compromise on the manufacturing test coverage**, and still keep a high throughput.

